

MODULE SCREENING TEST PLAN For Module H2

TEST	CONDITION	MIL-STD-750 TEST METHOD
Storage	$T_A = +150^{\circ}\text{C}$ for 24 hours	1032
Temp Cycle	-65°C to $+150^{\circ}\text{C}$, 10 cycles, 30 minutes each extreme	1051
Electrical	Reverse Current (I_R) @ rated V_{WM} Breakdown Voltage ($V_{(BR)}$) @ I_T	4016 4022
Pulse	20 pulses @ rated I_{PP} , $t_p = \text{rated}$	
Electrical	Reverse Current (I_R) @ rated V_{WM}	4016
Burn-In	$T_A = +125^{\circ}\text{C}$ @ rated V_{WM} for 96 hours	1038
Electrical	Reverse Current (I_R) @ rated V_{WM} , $D-I_R = 50\%$ or $1\mu\text{A}$, whichever is greater Breakdown Voltage ($V_{(BR)}$) @ I_T , $D-V_{(BR)} \pm 2\%$ from initial reading	4016 4022
Group A	Reverse Current (I_R) @ rated V_{WM} Breakdown Voltage ($V_{(BR)}$) @ I_T Clamping Voltage (V_C) @ I_{PP} , $t_p = \text{rated}$ Forward Voltage (V_F) @ I_F , $t_D = 8.3\text{ms}$	4016 4022 4011

Note: For bidirectional devices, test both polarities – split hours on Burn-in test and surge pulse to 50% each polarity.